

<b>Notice of References Cited</b>		Application/Control No.	Applicant(s)/Patent Under Reexamination KOLMAN ET AL.	
		Examiner Toan M. Le	Art Unit 2863	Page 1 of 1

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	B	US-6,681,351	01-2004	Kittross et al.	714/724
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	V	Ries, W., Rule-Based Implementation of Correct and Efficient VLSI Design Rule Checking, April 10-12, 1989, International Workshop on Industrial Application of Machine Intelligence and Vision, Pages 205-209
	W	Frevert et al., Use of HDL Code Checkers to Support the IP Entrance Check- A Requirement Analysis, 2002 IEEE, Proceedings of the Euromicro Symposium on Digital System Design
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\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.